

Search Notes



Application/Control No.

10/020,825

Examiner

Hien Tran

Applicant(s)/Patent under Reexamination

CRAIG ET AL.

Art Unit

1764

SEARCHED

Class	Subclass	Date	Examiner
422	176,177, 180	4/05	mr
60	324		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East Image Cl/sub search / Inv's names search / Text search	4/05	HT